

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

KANBE et al.

Atty. Ref.: 4034-38

Serial No. To be assigned

Group: Unknown

Filed: July 16, 2003

Examiner: Unknown

For: DISPLAY DEVICE

\* \* \* \* \*

July 16, 2003

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT**


As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

**NIXON & VANDERHYE P.C.**

By:



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**INFORMATION CLOSURE  
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

4034-38

To be assigned

APPLICANT

KANBE et al.

(Use several sheets if necessary)

FILING DATE

GROUP

July 16, 2003

Unknown

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,764,324	6/1998	Lu et al.			
	6,195,140	2/2001	Kubo et al.			

**FOREIGN PATENT DOCUMENTS**

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
11-101992	4/1999	Japan			ABSTRACT

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)**

	F. Nuesch et al., "A Photoelectron Spectroscopy Study on the Indium Tin Oxide Treatment by Acids and Bases," APPLIED PHYSICS LETTERS, Vol. 74, No. 6, 8 February 1999, pp. 880-882
	K. Sugiyama et al., "Dependence of Indium-Tin-Oxide Work Function on Surface Cleaning Method as Studied by Ultraviolet and X-Ray Photoemission Spectroscopies," JOURNAL OF APPLIED PHYSICS, Vol. 87, No. 1, 1 January 2000, pp. 295-298

\*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.